



JEOL JEM-2011 TEM

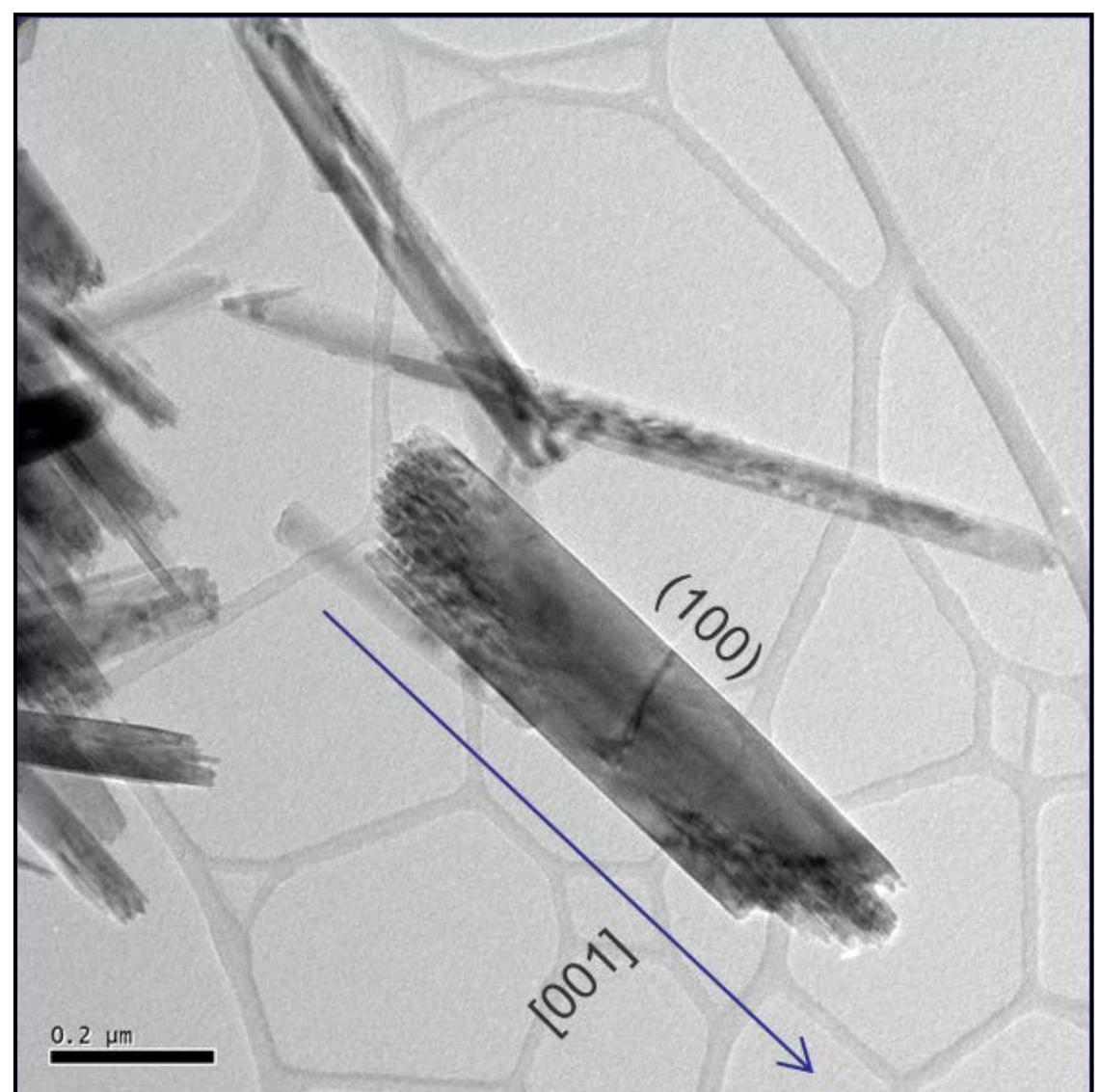
The JEM-2011 is a transmission electron microscope (TEM) with a LaB_6 filament. The TEM is equipped with an energy dispersive spectroscopy (EDS) x-ray detector and a scanning transmission electron microscope attachment. This combination allows for comprehensive elemental and micro-structural analysis at extremely high magnifications.

Application Examples

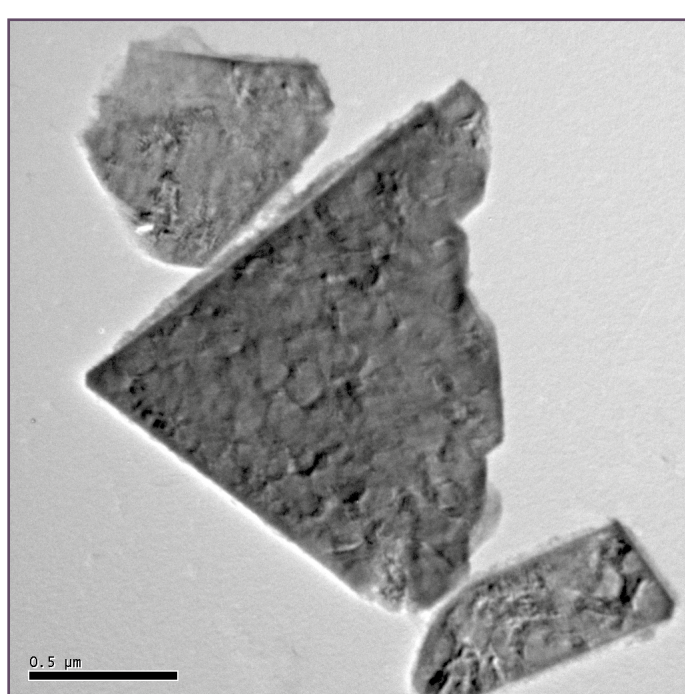
- Examination of ceramics for use in growing high temperature superconductive crystals
- Investigation of metal substitution in goethites
- Verifying unknown minerals by electron diffraction
- Studying the effects of viruses on the structure of cells

Key Capabilities

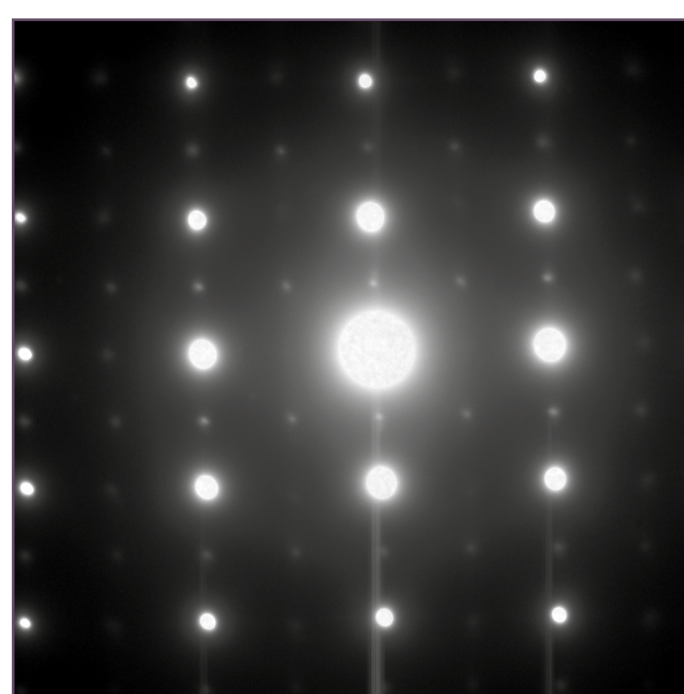
- High resolution bright field and dark field imaging
- Scanning Transmission Electron Microscope (STEM) imaging and analysis
- Selected Area Electron Diffraction (SAED)
- Energy Dispersive X-ray Spectroscopy (EDS) point analysis



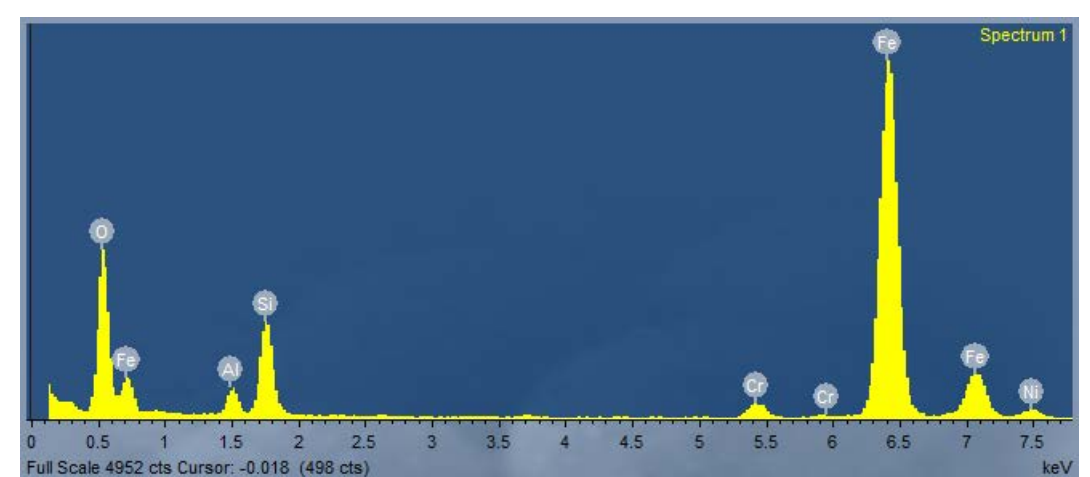
Bright field image of a geothite crystallite growing along the c-axis



Boehmite particles



Diffraction pattern of a boehmite particle



EDS spectrum of Ni- and Cr-substituted goethite in Western Australian laterite ore

For more information

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